



UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
UNITED STATES PATENT AND TRADEMARK OFFICE
WASHINGTON, D.C. 20231
www.uspto.gov

Paper No. 7

SUBRAMANIAN VENKAT SHASTRI
4373 MILLER AVENUE
PALO ALTO, CA 94306

BEST AVAILABLE COPY

COPY MAILED

In re Application of
Pelrine; Shastri; and Joseph
Application No. March 16, 2001
For: MICROLABORATORY DEVICES AND METHODS

DEC 13 2001
OFFICE OF PETITIONS

Dear Mr. Shastri:

You are named as a joint inventor in the above identified United States patent application, filed under the provisions of 35 U.S.C. 116 (United States Code), and 37 CFR 1.47(a), Rules of Practice in Patent Cases. Should a patent be granted on the application you will be designated therein as a joint inventor.

As a named inventor you are entitled to inspect any paper in the file wrapper of the application, order copies of all or any part thereof (at a prepaid cost per 37 CFR 1.19) or make your position of record in the application. Alternatively, you may arrange to do any of the preceding through a registered patent attorney or agent presenting written authorization from you. If you care to join in the application, counsel of record (see below) would presumably assist you. Joining in the application would entail the filing of an appropriate oath or declaration by you pursuant to 37 CFR 1.63.

Telephone inquiries regarding this communication should be directed to Wan Laymon at (703) 306-5685. Requests for information regarding your application should be directed to the File Information Unit at (703) 308-2733. Information regarding how to pay for and order a copy of the application, or a specific paper in the application, should be directed to Certification Division at (703) 308-9726 or 1 (800) 972-6382 (outside the Washington D.C. area).

Frances Hicks
Frances Hicks
Lead Petitions Examiner
Office of Petitions
Office of the Deputy Commissioner
for Patent Examination Policy

CC:
PERKINS COIE LLP
P.O. BOX 2168
MENLO PARK, CA 94025



UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
UNITED STATES PATENT AND TRADEMARK OFFICE
WASHINGTON, D.C. 20231
www.uspto.gov

Paper No. 6

PERKINS COIE LLP
P.O. BOX 2168
MENLO PARK, CA 94025

BEST AVAILABLE COPY

COPY MAILED

DEC 13 2001

In re Application of	:	OFFICE OF PETITIONS
Ronald E. Pelrine et al	:	
Application No. 09/810,919	:	DECISION GRANTING
Filed: March 16, 2001	:	STATUS UNDER 37 CFR
For: MICROLABORATORY DEVICES	:	1.47(a)
AND METHODS	:	

This is in response to the "Petition Under 37 CFR 1.47(a)," filed September 10, 2001.

The petition is granted.

Petitioner has shown that the non-signing inventor has refused to join in the filing of the above-identified application.

The above-identified application and papers have been reviewed and found in compliance with 37 CFR 1.47(a). This application is hereby accorded Rule 1.47(a) status. As provided in Rule 1.47(c), this Office will forward notice of this application's filing to the non-signing inventor at the address given in the petition. Notice of the filing of this application will also be published in the Official Gazette.

The Notice to File Missing Parts of Nonprovisional Application mailed June 7, 2001, additionally required the submission of substitute drawings in compliance with 37 CFR 1.84 because the "drawing sheets do not have the appropriate margin(s) (see 37 CFR 1.84(g)). Each sheet must have a top margin of at least 2.5 cm (1 inch), a right margin of at least 1.5 cm (5/8 inch), and a bottom margin of at least 1.0 cm (3/8 inch)." Therefore, timely compliance with this requirement must be made in order to avoid the abandonment of the application. The time for reply remains as set forth in the Notice of June 7, 2001.

Telephone inquiries regarding this decision should be directed to Petitions Examiner Wan Laymon at (703) 306-5685.

This application is being forwarded to Initial Patent Examination Division to await petitioner's reply to the Notice mailed June 7, 2001.

Frances Hicks
Frances Hicks

Lead Petitions Examiner
Office of Petitions
Office of the Deputy Commissioner
for Patent Examination Policy